

IN THE CLAIMS

1. (currently amended) A method for analyzing defect information on a substrate, the method comprising the steps of:
- inspecting the substrate to identify individual defect events, including at least one of defects, defective pixels, and ~~defective~~ defensive dice,
- 5 | classifying the individual defect events into event patterns, ~~include-including~~ at least one of defect clusters and spatial signatures,
- comparing the event patterns to a list of patterns of interest,
- logically dividing the substrate into zones,
- identifying the zones in which the patterns of interest exist on the substrate,
- 10 | comparing the identified zones to a list of zones of interest,
- identifying combinations of (1) patterns of interest on the substrate that (2) reside within zones of interest on the substrate, and
- comparing the identified combinations to a list of predetermined combinations that are associated with defect causes, and
- 15 | specifying at least one substrate defect cause based at least in part on matches between the identified combinations and the predetermined combinations and the associated defect causes.

2-20 (canceled)